

## "A best film thickness model in using interferometry in finding the pressure-viscosity coefficient alpha of a fluid"

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**Shell Global Solutions**

A best film thickness model in using interferometry

in finding the pressure-viscosity coefficient  $\alpha$  of a fluid

**TU/e**

technische universiteit eindhoven

Hamburg, June 19, 2009  
5<sup>th</sup> Arnold Tross Colloquium  
Harry van Leeuwen



## Presentation Outline

1. Introduction and aim
2. Analysis and methods
3. Results and Discussion
4. More homework ....
5. Results and Discussion (continued)
6. Conclusions

## 1. Introduction and aim (1)

Why?

- In many lubricated tribosystems the pressure-viscosity coefficient ( $\alpha$ ) is important but not known
- This is especially true for hard EHL contacts (having high moduli of elasticity and very high contact pressures)  $\Rightarrow$  a guess easily leads to gross errors in the film thickness
- In addition, the pressure dependency of fluids is becoming more and more important. Think of common rail injection of diesel fuel, soon at 3,000 bars (0.3 GPa)

## 1. Introduction and aim (3)

Pressure viscosity coefficients for high pressures are determined at a few institutes only, e.g.

- at the Center for High Pressure Rheology of Georgia Tech, Atlanta (Scott Bair), or
- at Luleå University (Eric Höglund),
- at the RWTH Aachen (Peter Gold) or
- at the TU Clausthal (Hubert Schwarze)

To calculate EHL films the value of  $\alpha$  has to be known.

Central question:

*How can  $\alpha$  be determined, having film thickness measurement equipment and some tribological knowledge?*

## 1. Introduction and aim (2)

We want to find the (generalized) pressure-viscosity coefficient:

$$\alpha^* = \left( \int_0^{\infty} \frac{\eta_0}{\eta(p)} dp \right)^{-1} \quad (\text{Blok})$$

where

$\eta$  the dynamic viscosity (Pa.s)

$\eta_0$  the dynamic viscosity at  $p = 0$  (Pa.s)

$\alpha^*$  the reciprocal asymptotic isoviscous pressure, (Pa<sup>-1</sup>)

.... a proven good estimate of  $\alpha$

For the simple Barus relationship:

$$\eta = \eta_0 e^{\alpha p} \Rightarrow \alpha = \frac{1}{\eta} \frac{\partial \eta}{\partial p} \quad (\text{Barus})$$

for a Barus relationship:  $\alpha^* = \alpha$

## Overview

1. Introduction and aim
2. **Analysis and methods**
3. Results and Discussion
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## 2. Analysis and methods

The idea, already coined at the occasion of the III<sup>rd</sup> Arnold Tross Colloquium on June 8<sup>th</sup>, 2007:

### **Determine $\alpha$ through film thickness:**

- perform film thickness measurements (all conditions known, except  $\alpha$ )
- calculate these film thickness values by employing methods from numerical analysis, or approximation formulas
- assume a value for  $\alpha$  which minimizes the error between measurement and calculation for all measurements

### **Now needed:**

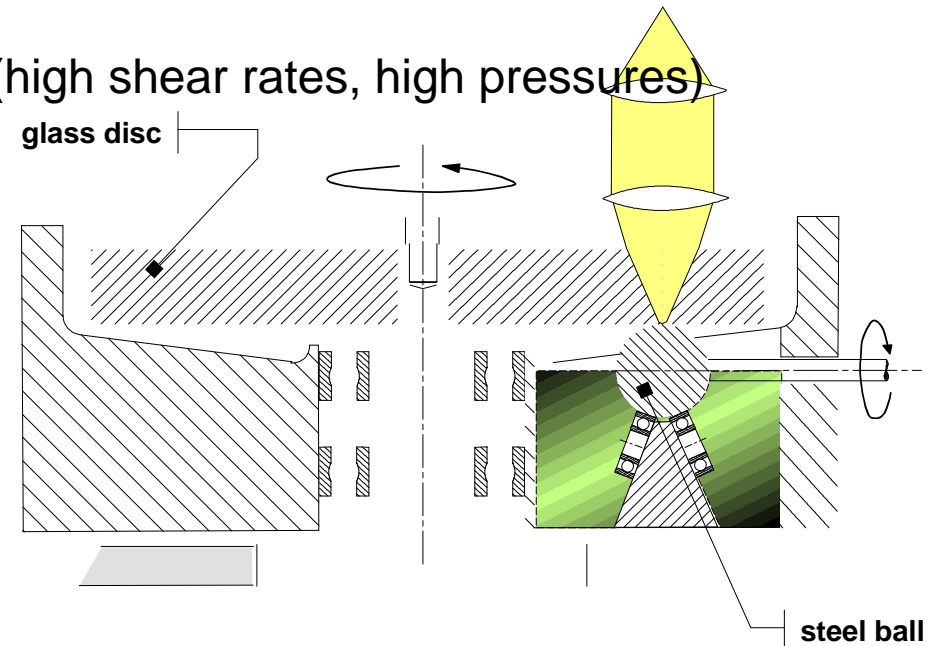
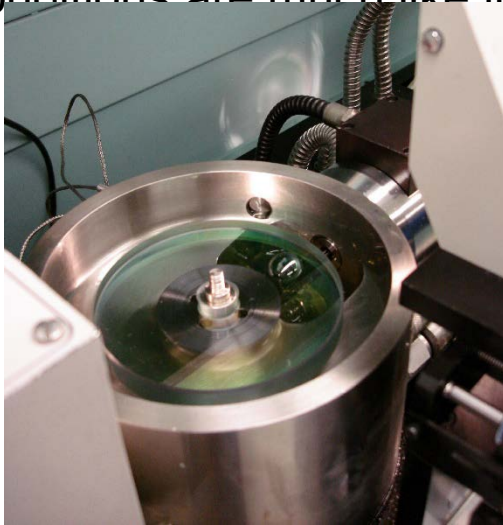
- an accurate film thickness measurement method
- an accurate film thickness problem solver or formula



## 2. Analysis and methods (2)

### Advantages:

- Shell got such an accurate film thickness measuring device (a PCS Instruments Ultra Thin Film Measurement System, at Shell Westhollow, in Houston, TX)
- in general, film thickness rigs are more widely spread over the world than high pressure viscometers
- conditions are much like in practice (high shear rates, high pressures)



Figures: PCS Instruments EHL Ultra Thin Film Measurement System

## 2. Analysis and methods (3)

Abbe's limit:

$$h > \frac{1}{4} \lambda \approx 100 \text{ nm} = 0.1 \text{ } \mu\text{m}$$

But: the inaccuracy of the measurement is less than 1 nm.

Now a trick is exploited:  
spacer layer of  $500 \text{ nm} = 0.5 \text{ } \mu\text{m}$   
allows  $1 < h < 100 \text{ nm}$

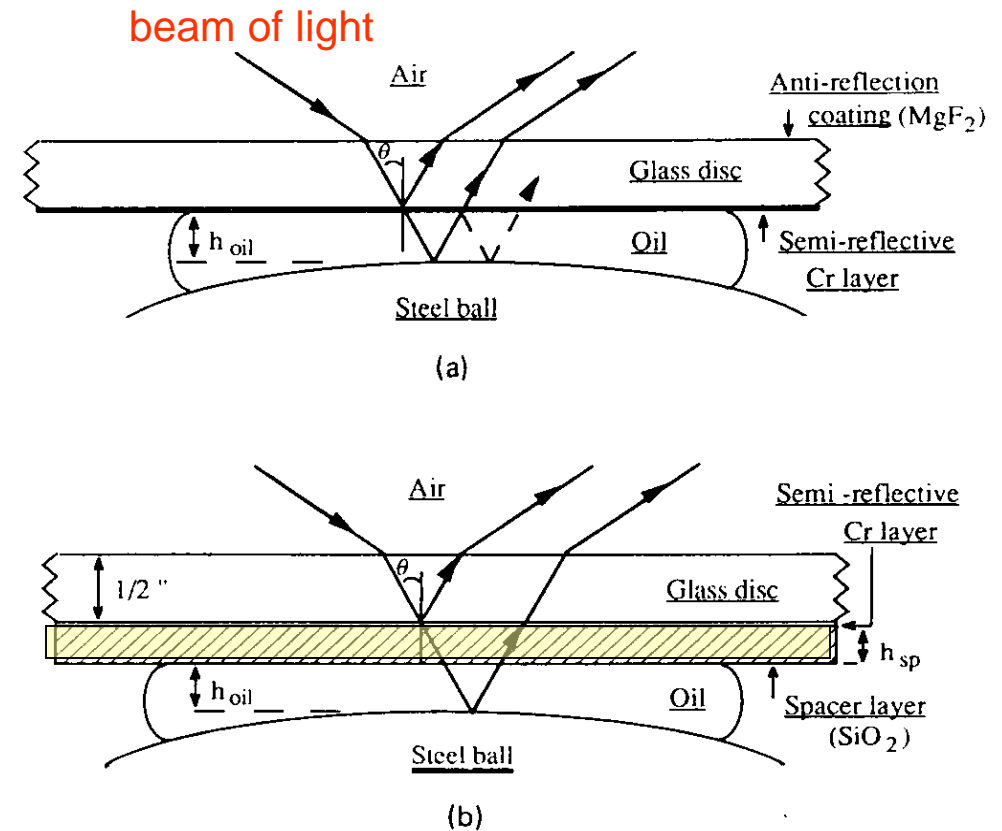


Fig. 1—(a) Basic interferometric method (two beam).  
(b) Spacer layer method.

Source: Johnston et al., 1991

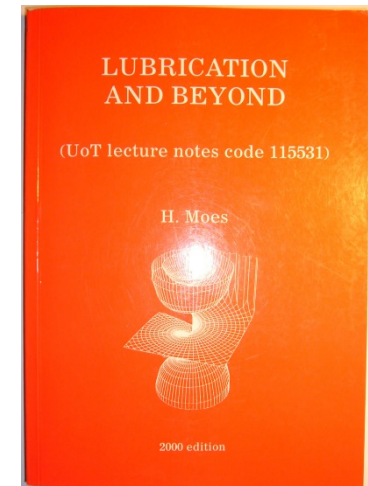
## 2. Analysis and methods (4)

### *The measurements part.*

- a PCS Instruments EHL Ultra Thin Film Measurement System.
- This allows measurement of the central film thickness with an inaccuracy down to 1 nm.

### *The calculation part.*

Back in 2007, is from a Textbook by Moes (2000), which provides an estimate of the central film thickness in nonconformal contacts, with claimed small inaccuracy (better than 10% **everywhere**)



## 2. Analysis and methods (5)

Using the nondimensional groups now so common in EHL work, originally from Blok (1960) and Moes (1965), adapted for elliptical contacts, yields:

$$\text{film thickness group } \hat{H} = \left( \frac{h}{R_e} \right) \left( \frac{E_r R_e}{2\eta_0 \bar{u}} \right)^{\frac{1}{2}}$$

$$\text{load group } M = \left( \frac{F}{E_r R_e^2} \right) \left( \frac{E_r R_e}{2\eta_0 \bar{u}} \right)^{\frac{3}{4}}$$

$$\text{lubricant group } L = (\alpha E_r) \left( \frac{2\eta_0 \bar{u}}{E_r R_e} \right)^{\frac{1}{4}}$$

$$\text{ellipticity group } \omega = \left( \frac{R_t}{R_e} \right) \Rightarrow \text{here } \omega = 1$$

Moes (2000) finds  $\Rightarrow$

$$\hat{H}_c = \left[ \left\{ \hat{H}_{IR}^{\frac{3}{2}} + \left( \hat{H}_{IE}^{-4} + 0.1\omega^{-4} \right)^{-\frac{3}{8}} \right\}^{\frac{2}{3}\hat{s}} + \left( \hat{H}_{VR}^{-8} + \hat{H}_{VE}^{-8} \right)^{-\frac{1}{8}\hat{s}} \right]^{\frac{1}{6}}$$

where

$$\hat{s} = \frac{3}{2} \left\{ 1 + \exp \left( -1.2 \frac{\hat{H}_{IE}}{\hat{H}_{IR}} \right) \right\}$$

$$\text{and } \hat{H}_c = \hat{H}_c(M, L, \omega)$$

## 2. Analysis and methods (6)

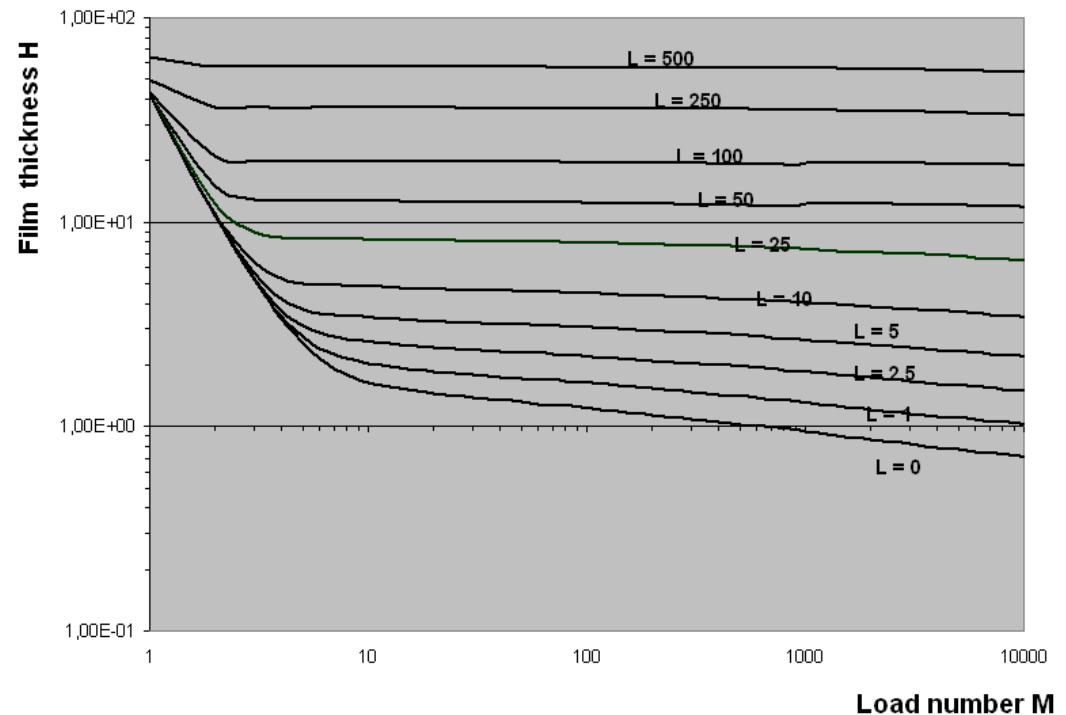
Moes states that in a domain  $5 \leq M \leq 1000$ ,  $0 \leq L \leq 25$  for a circular contact the inaccuracy of his latest approximation formula is  $e < 10\%$

The advantages:

- one formula fits all: an enormous range of conditions, even beyond practice
- looks attractive

For a circular contact  $\Rightarrow$

**But why  
should we believe  
these claims?**



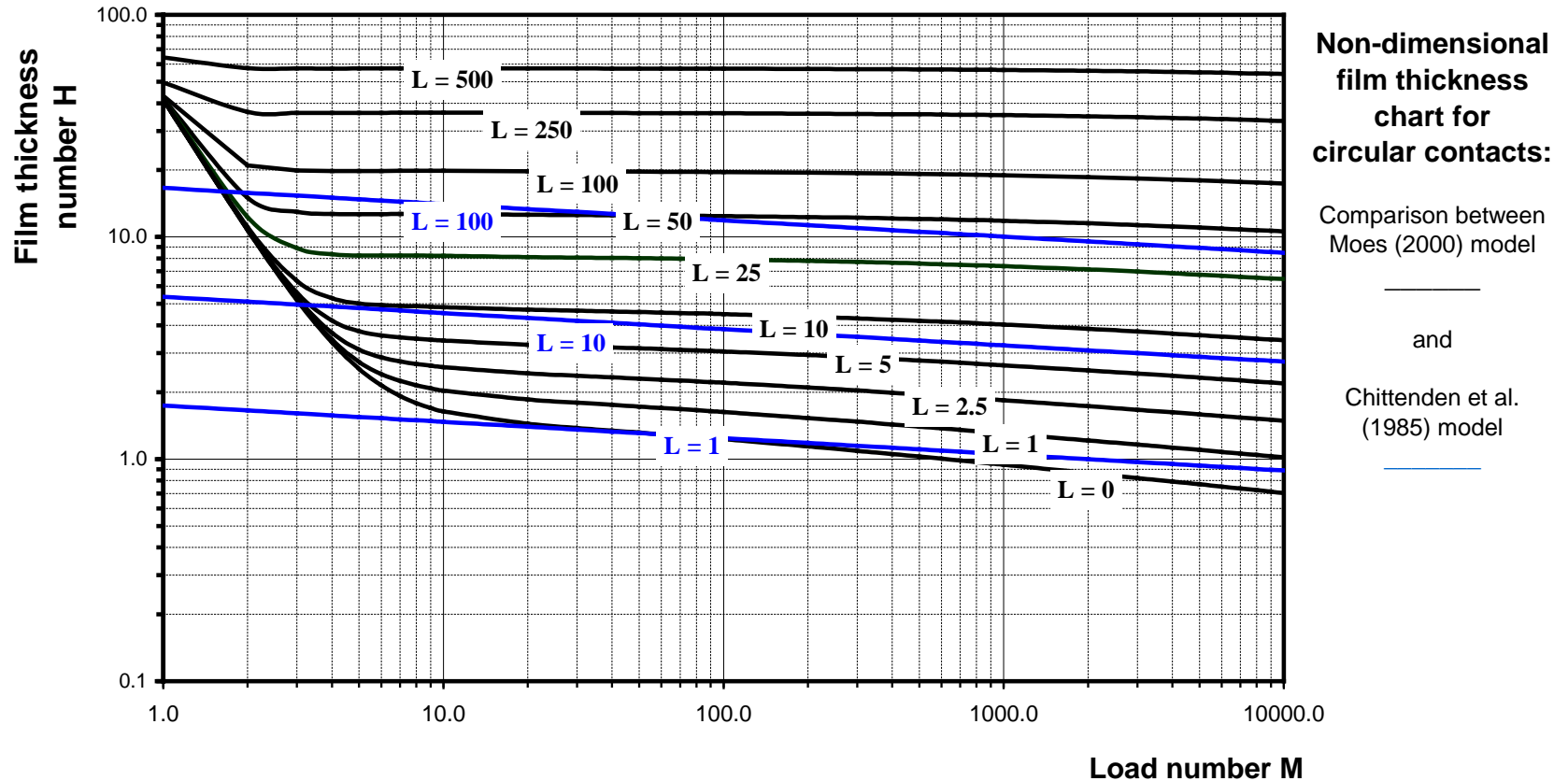
## 2. Analysis and methods (7)

Many more film thickness model equations exist:

- Archard and Cowking (1965) for circular hard contacts
- Hamrock and Dowson (1977, 1981) for circular and short elliptical contacts
- Hamrock et al. (2004) and Hamrock (1994) for circular and short elliptical contacts
- Chittenden et al. (1985) for circular and long elliptical contacts
- Hooke (1988)
- Sutcliffe (1989) for arbitrary elliptical contacts
- Greenwood (1988) for circular contacts
- Venner (1991), and Venner and Ten Napel (1992) for circular contacts
- Nijenbanning, Venner and Moes (1994) for circular and short elliptical contacts
- Venner and Lubrecht (2000) for circular contactsst
- Moes (2000) for arbitrary elliptical contacts

**Is the Moes film model equation really the best one?**

## 2. Analysis and methods (8)



Contour map of  $H(M,L)$  showing lines of constant film thickness for Moes and Chittenden film models

## 2. Analysis and methods (9)

A comparison of some models for  $L = 10$ : large differences

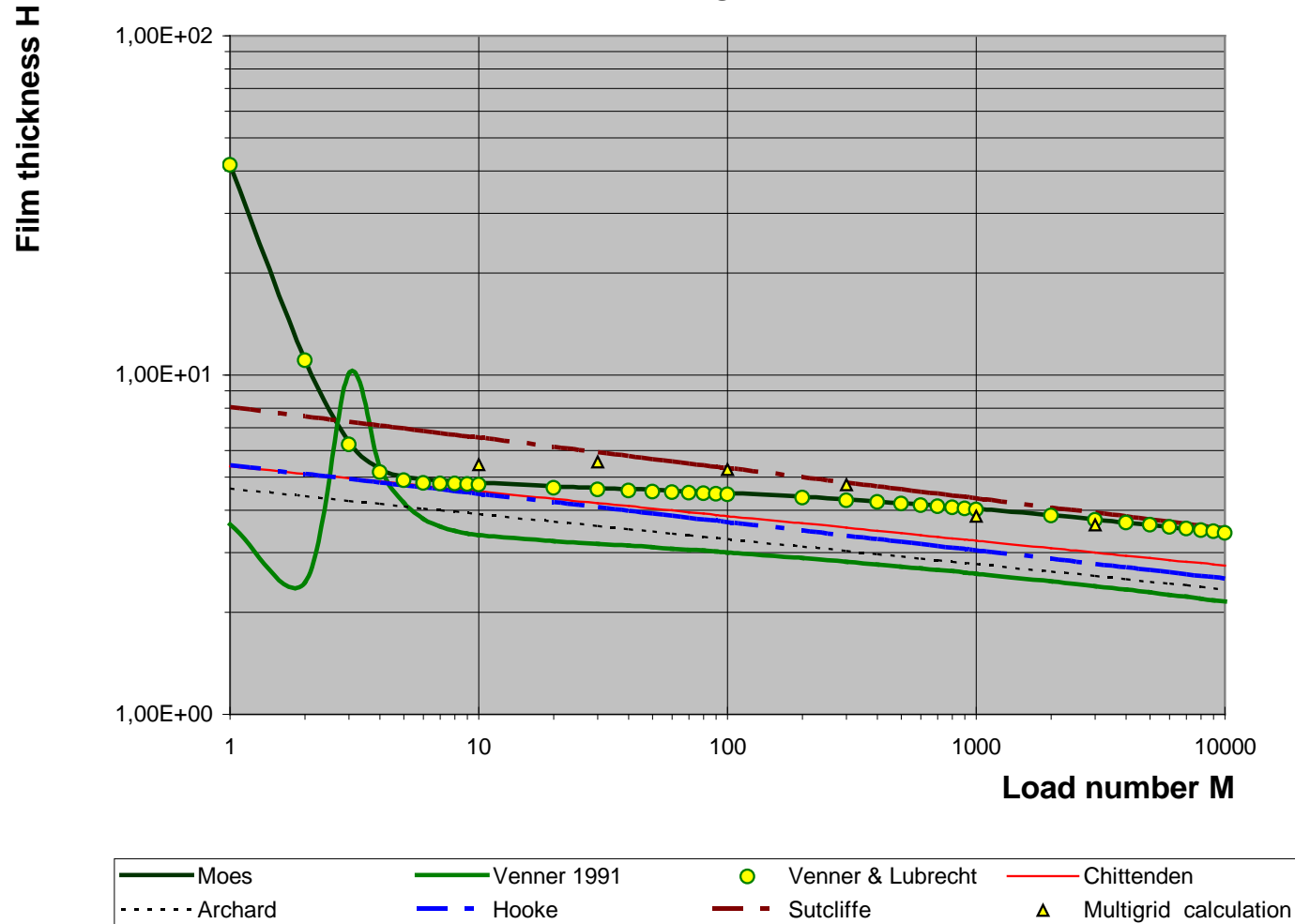


Figure: Nondimensional film thickness vs.  $M$  for  $L = 10$



## Overview

1. Introduction and aim
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3. **Results and Discussion**
4. More homework ....
5. Results and Discussion (continued)
6. Conclusions

### 3. Results and Discussion

At the 3<sup>rd</sup> Arnold Tross Colloquium in 2007 we showed for the results for a base oil (a blend with unknown  $\alpha$  value) the following results

- using the latest Moes (2000) formula,
- at 0.71 GPa and different temperatures

<b>Base oil A @ 0.714 Gpa</b>			
temperature °C	estimate for $\alpha$ (GPa <sup>-1</sup> )	stdrd dev in $h_{\text{centr}}$	correlation $R^2$
30	25.51	1.733E-08	0.99583
40	22.22	1.163E-08	0.99814
60	18.52	6.303E-09	0.99749

### 3. Results and Discussion (2)

For base oil A, we can now fit  $\alpha$  for pressures and temperatures of interest, e.g.:

Central Film Thickness Base Oil A at 50N and different temperatures

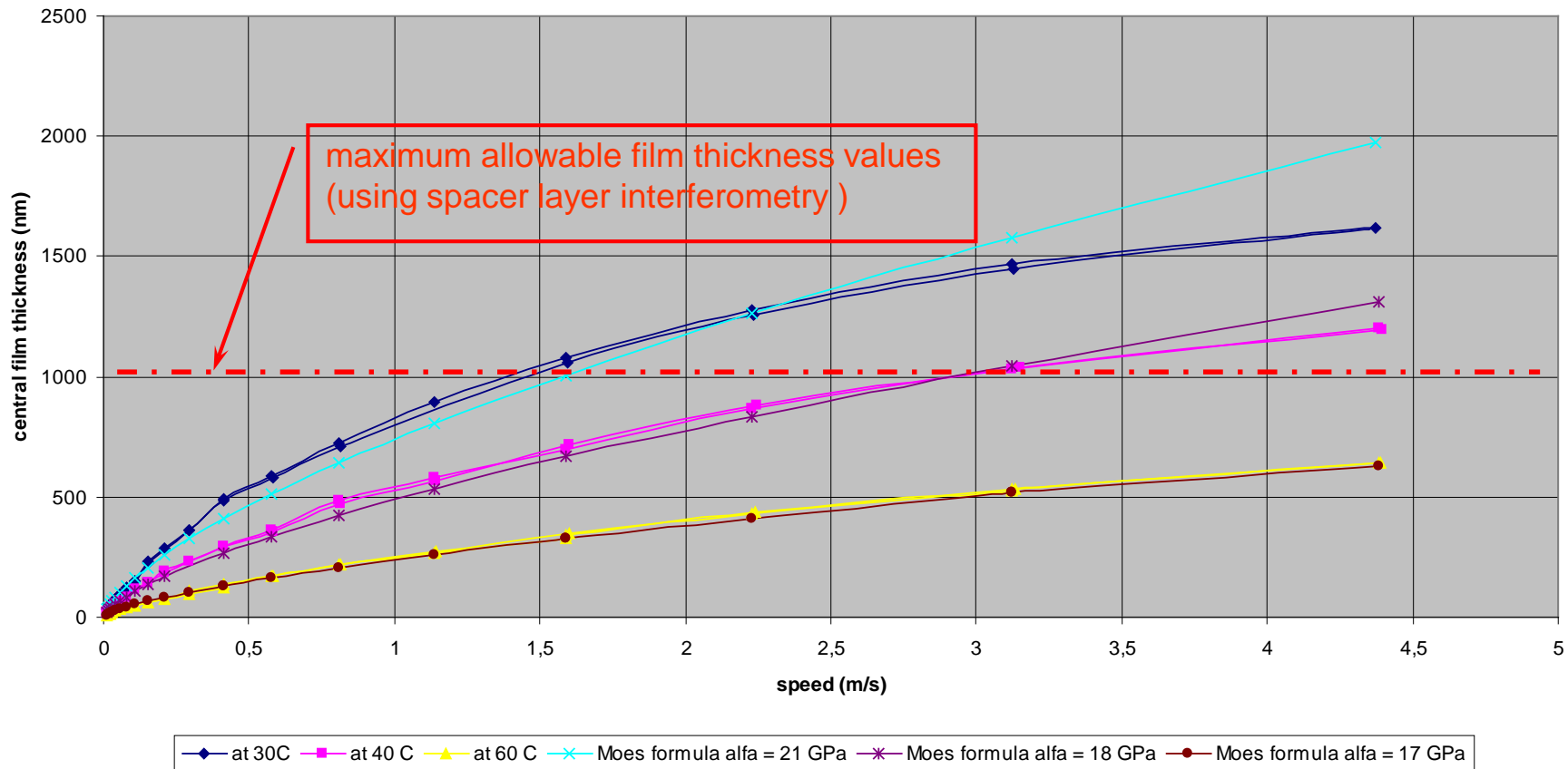


Figure: Central film thickness with rolling speed for base oil A

### 3. Results and Discussion (3)

And that's it.

Conclusions:

- the PCS system works in an enormous range of EHD conditions
- the Moes (2000) formula can be used in an enormous range of conditions
- measurement results can be fitted by the best choice of  $\alpha$ , which allows the PCS system to be used as a versatile alternative to determine the pressure viscosity coefficient

Ready (in 2007).

*Or .....?*

**It is unknown whether the estimated value of  $\alpha$  equals the real value or not!**

## Overview

1. Introduction and aim
2. Analysis and methods
3. Results and Discussion
4. **More homework ....**
5. Results and Discussion (continued)
6. Conclusions

## 4. More homework ....

How can we be sure that the calculated  $\alpha$  value is indeed the best one?

⇒ use a lubricant with known pressure-viscosity characteristics and run the same procedure

Let's use HVI60. This oil has  $\alpha = 19.8 \text{ GPa}^{-1}$  at  $40 \text{ }^{\circ}\text{C}$

And, while doing this, why not run some other film thickness models?

Eleven (11) models will be tested on HVI60, almost all the literature has to offer:

- 1) Archard and Cowking (1965)
- 2) Hamrock and Dowson (1977, 1981)
- 3) Hamrock (1994) and Hamrock et al. (2004)
- 4) Chittenden et al. (1985)
- 5) Hooke (1988)
- 6) 'implied' Greenwood (1988)
- 7) Sutcliffe (1989)
- 8) Venner (1991), and Venner and Ten Napel (1992)
- 9) Nijenbanning, Venner and Moes (1994)
- 10) Venner and Lubrecht (2000)
- 11) Moes (2000)

## 4. More homework (2)

Series 08 (all exp) central film thickness HVI 60 at 0.53 GPa and 20N Series 0804

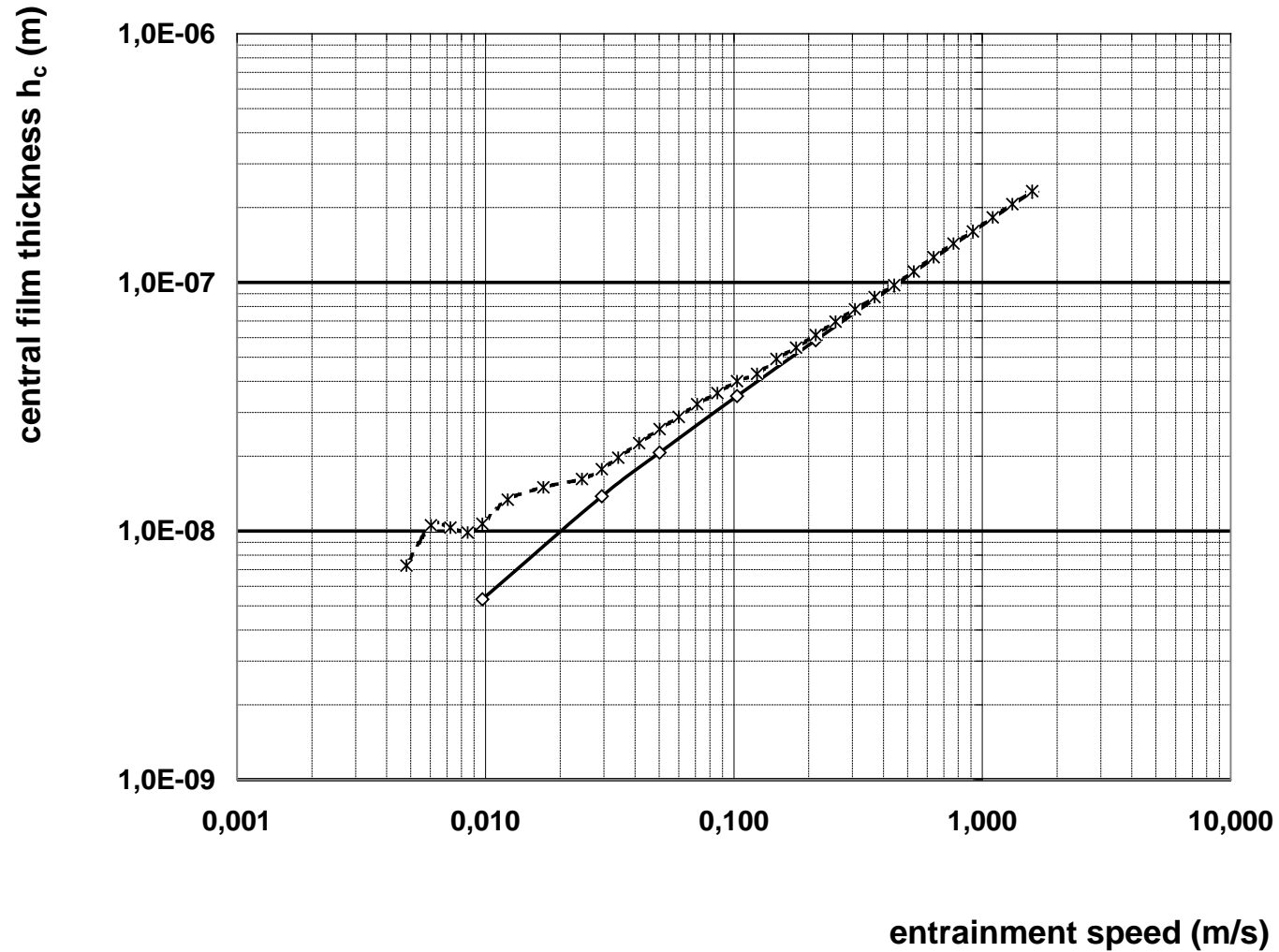


Figure: Data to be used. Central film thickness from experiments (x-x-x) and full multigrid calculations (Ⓛ-Ⓛ-Ⓛ) vs. speed (series 2008)

## Overview

1. Introduction and aim
2. Analysis and methods
3. Results and Discussion
4. More homework ....
5. **Results and Discussion (continued)**
6. Conclusions

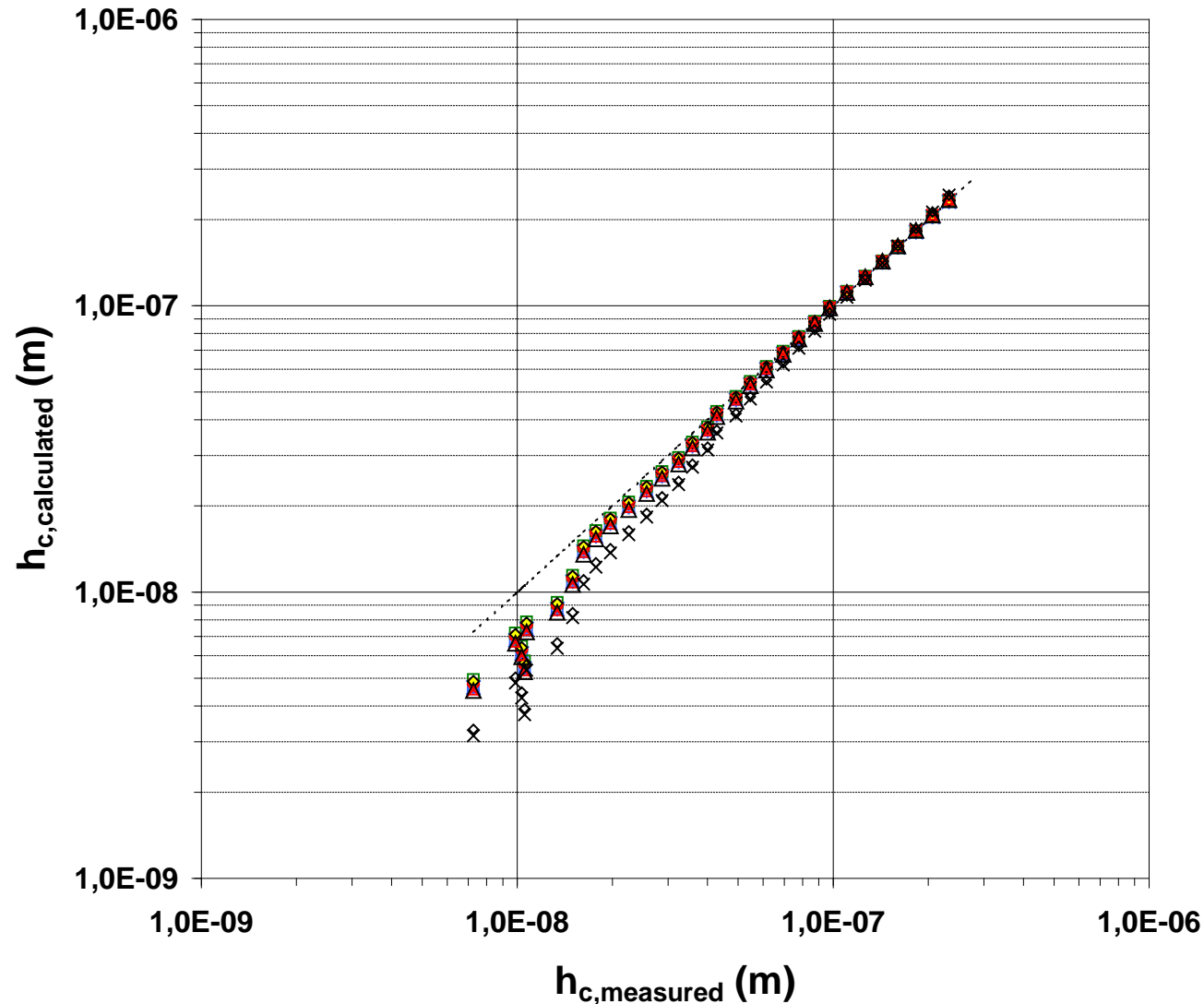


## 5. Results and Discussion (continued)

For a film thickness measurement series of HVI60 oil at 40 °C:

For linear film thickness values model		estimate for $\alpha^*$ (Pa <sup>-1</sup> )	stdrd dev in lin $h_{\text{centr}}$	correlation $R^2$	deviation 1,98E-08
1	<i>Archard and Cowking</i>	2,92E-08	6,05E-09	0,9920	47,4%
2	<i>Hamrock &amp; Dowson</i>	1,83E-08	2,34E-09	0,9987	-7,7%
3	<i>Hamrock et al.</i>	1,83E-08	2,76E-09	0,9982	-7,5%
4	<i>Chittenden et al.</i>	1,96E-08	2,76E-09	0,9982	-1,0%
5	<i>Hooke</i>	2,50E-08	6,59E-09	0,9905	26,3%
6	<i>Sutcliffe</i>	1,42E-08	2,95E-09	0,9979	-28,0%
7	<i>Greenwood</i>	1,82E-08	2,22E-09	0,9988	-7,9%
8	<i>Venner</i>	1,57E-08	2,17E-09	0,9989	-20,6%
9	<i>Nijenbanning et al.</i>	1,50E-08	2,72E-09	0,9982	-24,2%
10	<i>Venner &amp; Lubrecht</i>	1,59E-08	2,54E-09	0,9985	-19,6%
11	<i>Moes</i>	1,50E-08	2,72E-09	0,9982	-24,1%

## 5. Results and Discussion (continued 2)



**Logarithmic scales for  
 $h_{\text{calculated}}$  vs  $h_{\text{measured}}$   
with best fit of a  
for each film thickness  
approximation  
series 08 (all exp)**

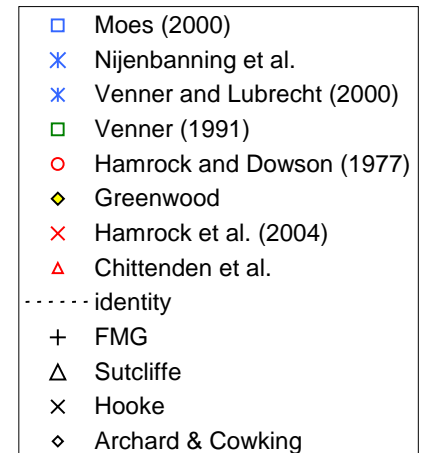
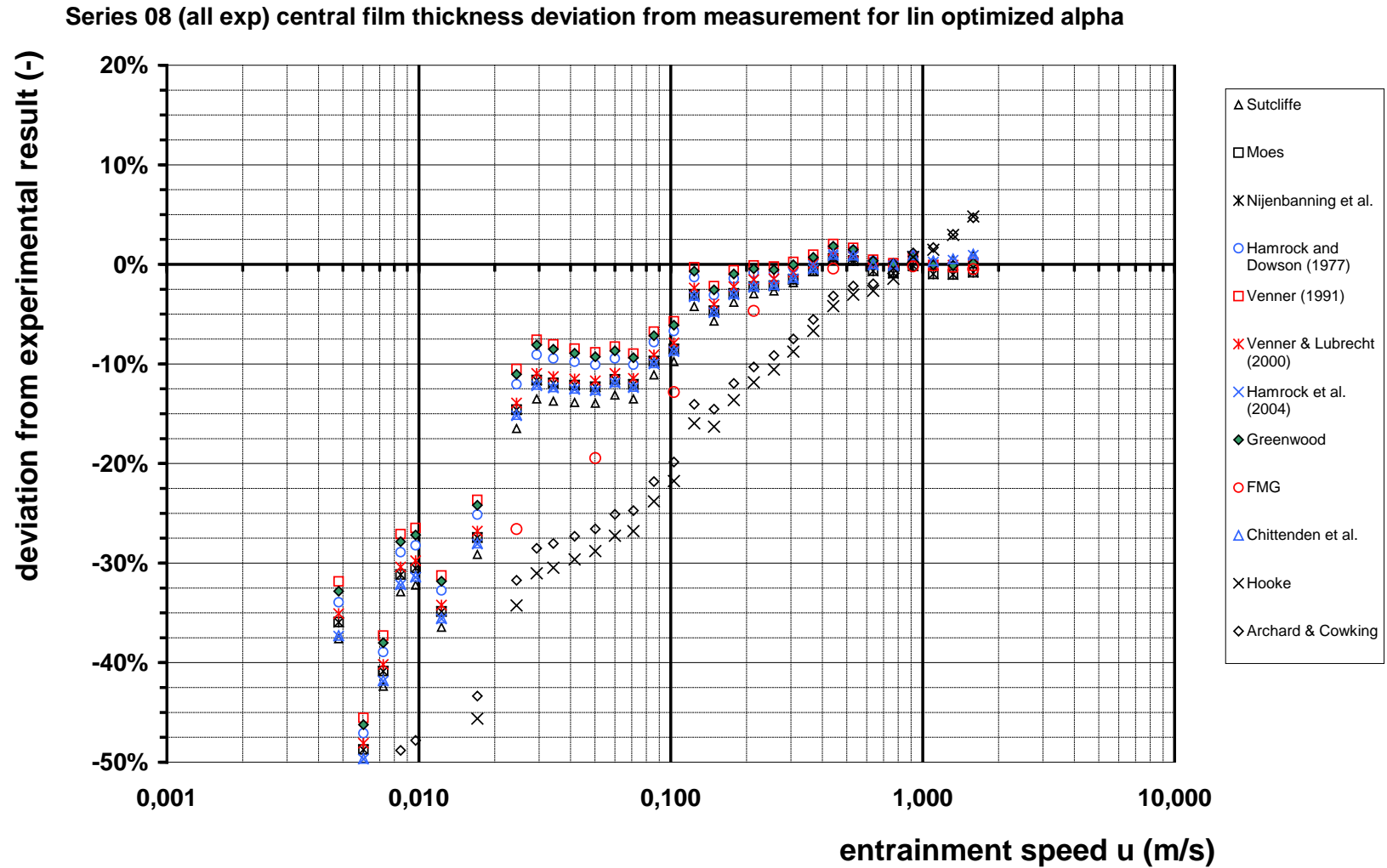


Figure: The central film thickness from formulas and full multigrid calculations vs. the measured value (series 2008)

## 5. Results and Discussion (continued 3)



## 5. Results and Discussion (continued 4)

Many more figures, same pattern:

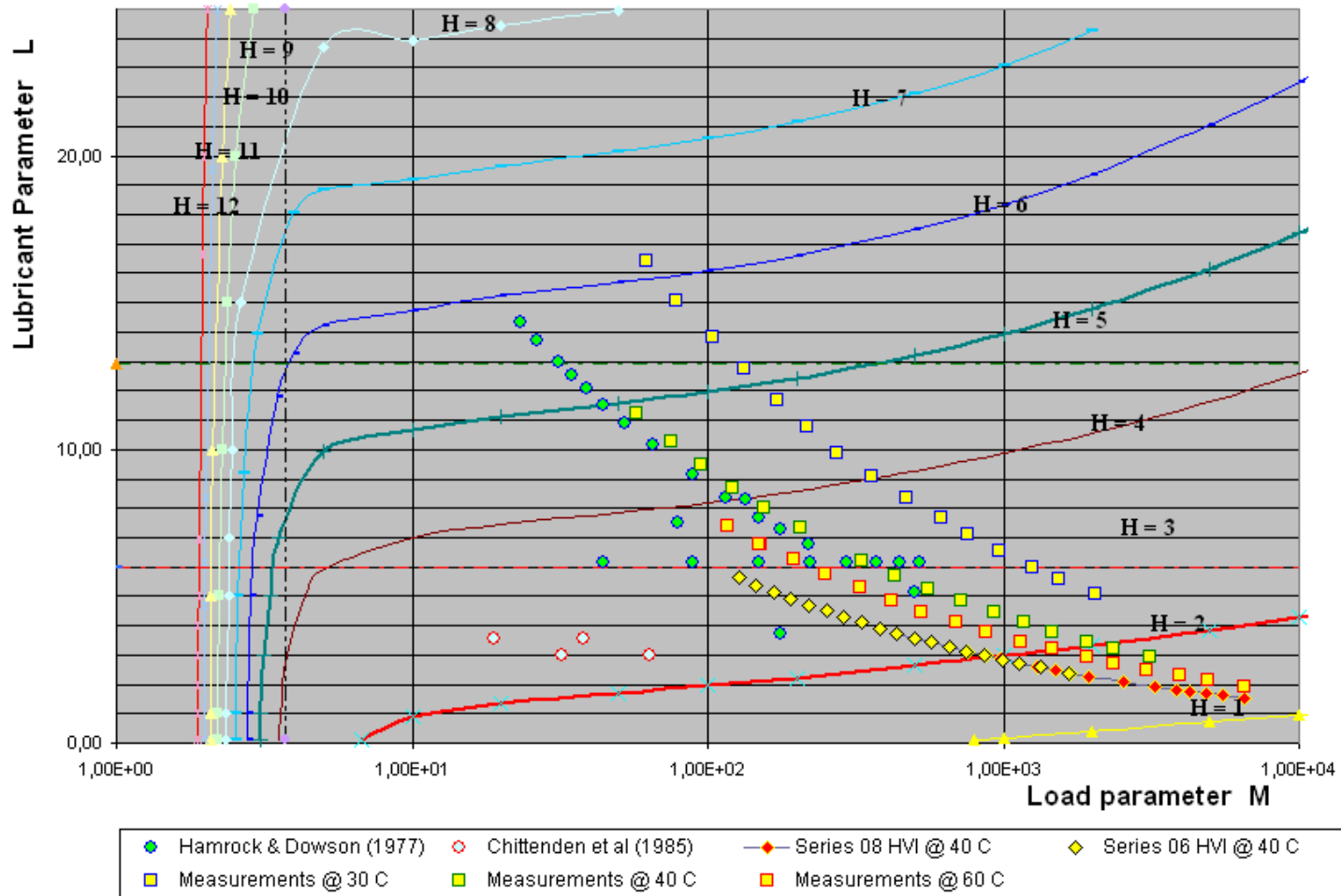
- At thin films the Moes formulas are closer to the measurement than at thick ones ( $< 30\text{-}40\text{ nm} \Rightarrow$  odd)
- The best overall performer is the Chittenden et al. (1985) formula, the Hamrock & Dowson (1977) is close.

Why?

Let us take a look at the (L,M) domain. The Chittenden work is based on their own calculations and Hamrock & Dowson's, see the next Figure, which has been drawn using Moes (2000) equations

## 5. Results and Discussion (continued 5)

### Nondimensional Film Thickness Map for a Circular Contact



## 5. Results and Discussion (continued 6)

Hence

- a good approximation formula -seen from a statistical viewpoint-, is not a guarantee that it also is the best tribological tool. Beyond statistical arguments, the accuracy of the result is the most decisive factor,
- the Chittenden et al. (1985) approximation performed best out of 11 models tested in a domain  $2 < L < 7$ ,  $20 < M < 7000$ . The regime  $L > 7$  has not been explored yet for a fluid with a priori known alpha value

## 5. Results and Discussion (continued 7)

Now, what about that base oil A?

$\alpha$ through lin film thickness		Base oil A @ 0.7 GPa and 30 °C			Base oil A @ 0.7 GPa and 40 °C			Base oil A @ 0.7 GPa and 60 °C		
<i>model</i>		estimate for $\alpha$ (GPa)	stdrd dev in lin $h_{centr}$	correlation $R^2$	estimate for $\alpha$ (GPa)	stdrd dev in lin $h_{centr}$	correlation $R^2$	estimate for $\alpha$ (GPa)	stdrd dev in lin $h_{centr}$	correlation $R^2$
1	<i>Archard and Cowking</i>	3.789E-08	2.102E-08	0.99431	3.350E-08	2.444E-08	0.99231	3.212E-08	6.936E-09	0.99719
2	<i>Hamrock &amp; Dowson</i>	3.236E-08	1.939E-08	0.99466	2.550E-08	2.159E-08	0.99289	2.300E-08	7.122E-09	0.99678
3	<i>Hamrock et al.</i>	3.148E-08	1.826E-08	0.99536	2.497E-08	1.987E-08	0.99413	2.236E-08	6.546E-09	0.99728
4	<i>Chittenden et al.</i>	3.570E-08	1.827E-08	0.99535	2.993E-08	1.301E-08	0.99765	2.496E-08	6.414E-09	0.99742
5	<i>Hooke</i>	3.221E-08	2.250E-08	0.99356	2.845E-08	2.643E-08	0.99109	2.766E-08	7.625E-09	0.99664
6	<i>Sutcliffe</i>	2.310E-08	1.604E-08	0.99647	1.712E-08	3.633E-08	0.97890	1.731E-08	5.626E-09	0.99806
7	<i>Venner</i>	2.644E-08	1.764E-08	0.99565	2.318E-08	1.213E-08	0.99798	1.933E-08	6.656E-09	0.99718
8	<i>Nijenbanning et al.</i>	2.539E-08	1.735E-08	0.99580	2.220E-08	1.164E-08	0.99814	1.846E-08	6.356E-09	0.99744
9	<i>Venner &amp; Lubrecht</i>	2.583E-08	1.736E-08	0.99580	2.262E-08	1.177E-08	0.99810	1.896E-08	6.301E-09	0.99749
10	<i>Moes</i>	2.551E-08	1.733E-08	0.99583	2.222E-08	1.163E-08	0.99814	1.852E-08	6.303E-09	0.99749

## 6. Conclusions & Recommendations

- Eleven approximation formulas for the central film thickness in EHL circular contacts have been compared. In the measurement range of this study **the Chittenden et al. (1985) formula proved to be the best**, and related formulas as from Hamrock and Dowson (1977) and Hamrock et al. (2004) are close.
- The Chittenden et al. formula for central film thickness can be used for estimating the value of the pressure-viscosity coefficient of a lubricant through an interferometric device with proper accuracy.
- The validity of the Chittenden et al. formula transcends the area where it was originally designed for.
- Experiments with a lubricant having a known  $\alpha$  value, at high L and medium M values, are needed to find out which model is best in the upper part of the (L,M) domain
- The Moes formulas are the most versatile and general ones available, but in the range of the measurements they lack the accuracy of the Chittenden approximation.
- More and better numerical data in a wide area in the (L,M) domain, available at present, provide a basis for a better approximation formula, which yields an increased accuracy in the determination of  $\alpha$ .



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## Reference:

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